

Measurement Report for Device, EDGE TOP, U-NII 3, Channel 149 (5745.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE TOP, 10.00	U-NII 3		5745.000, 149	4.95	5.17	35.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

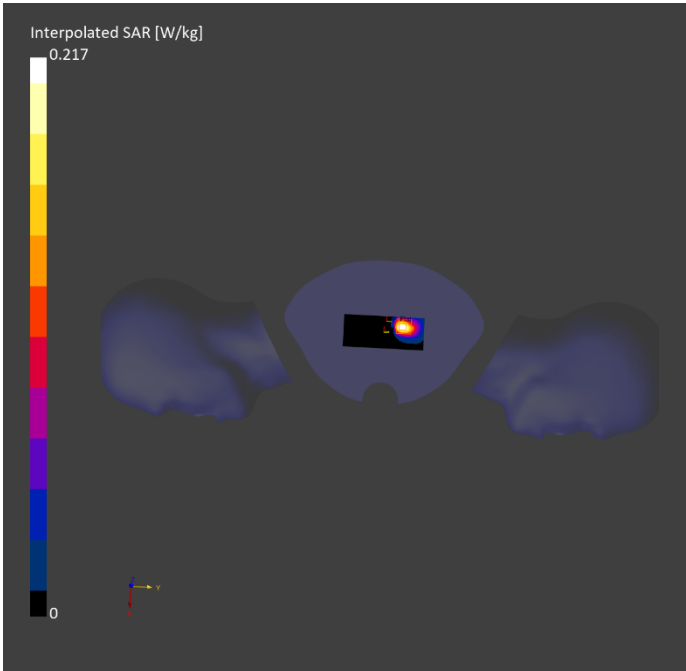
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-09-07	2026-09-07
psSAR1g [W/kg]	0.158	0.170
psSAR10g [W/kg]	0.058	0.058
Power Drift [dB]	-0.12	-0.25
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		55.3
Dist 3dB Peak [mm]		9.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, GSM 850, Channel 251 (848.800MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, Head Simulating Liquid	CHEEK, 0.00	GSM 850		848.800, 251	9.41	0.914	43.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

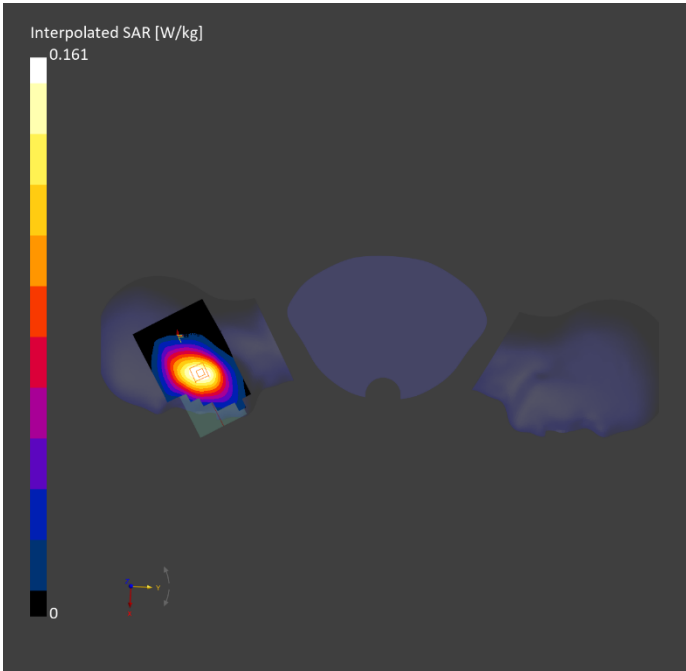
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-20	2026-08-20
psSAR1g [W/kg]	0.141	0.153
psSAR10g [W/kg]	0.098	0.120
Power Drift [dB]	-0.02	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		91.4
Dist 3dB Peak [mm]		26.3

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, GSM 850, Channel 251 (848.800MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 10.00	GSM 850		848.800, 251	9.41	0.914	43.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

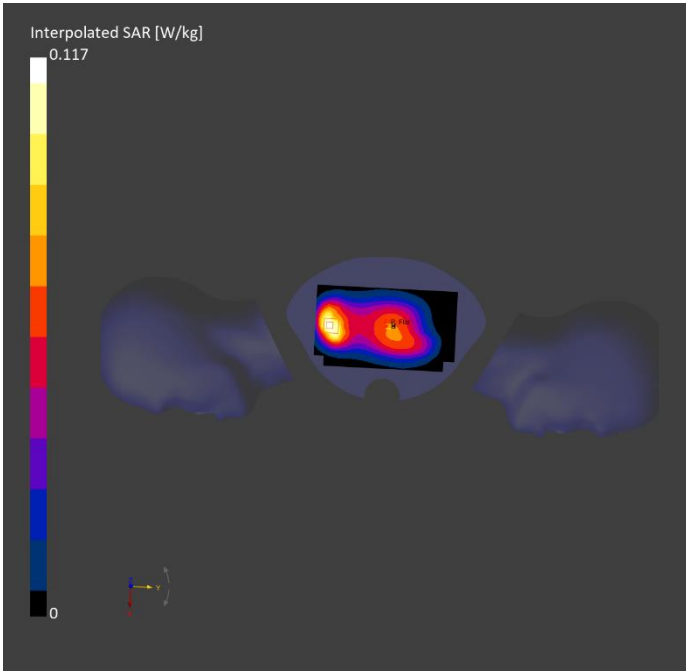
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-20	2026-08-20
psSAR1g [W/kg]	0.100	0.103
psSAR10g [W/kg]	0.066	0.063
Power Drift [dB]	-0.00	-0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.1
Dist 3dB Peak [mm]		13.5

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, PCS 1900, Channel 512 (1850.200MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	CHEEK, 0.00	PCS 1900		1850.200, 512	7.68	1.42	41.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

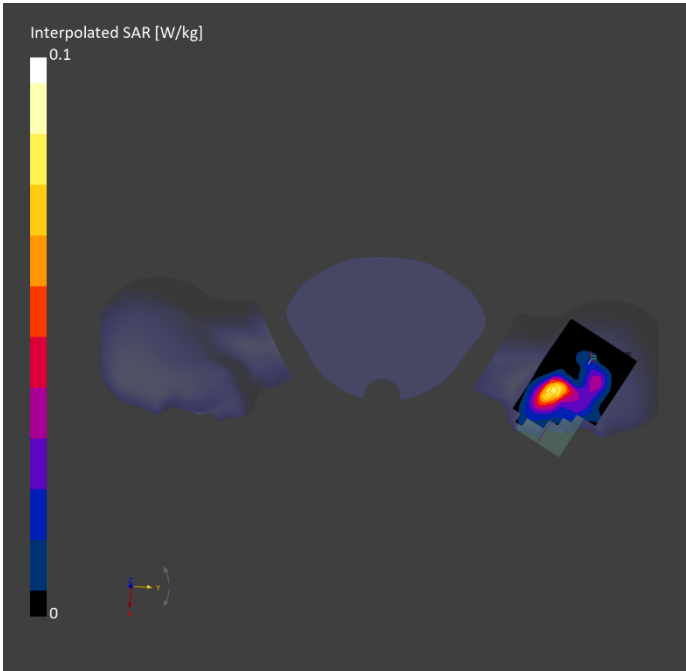
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-26	2026-08-26
psSAR1g [W/kg]	0.069	0.074
psSAR10g [W/kg]	0.041	0.047
Power Drift [dB]	0.07	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		89.7
Dist 3dB Peak [mm]		14.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE BOTTOM, PCS 1900, Channel 512 (1850.200MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE BOTTOM, 10.00	PCS 1900		1850.200, 512	7.68	1.42	41.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

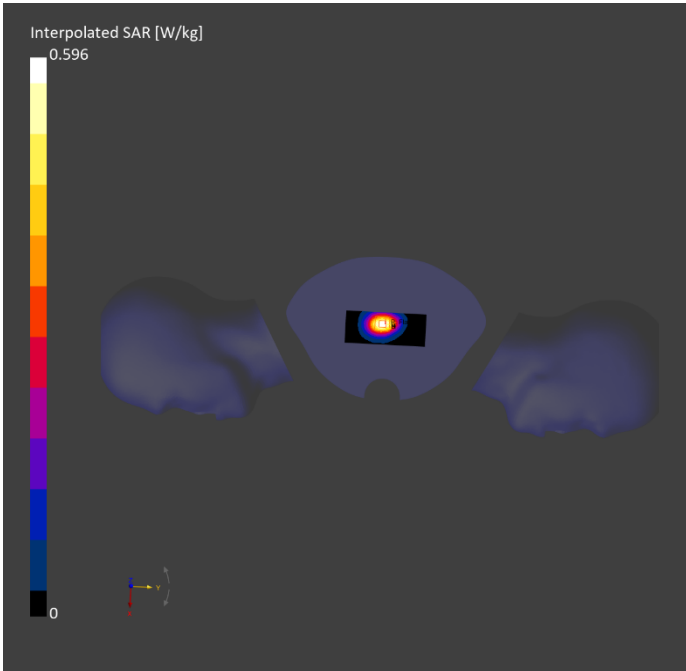
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-26	2026-08-26
psSAR1g [W/kg]	0.485	0.513
psSAR10g [W/kg]	0.267	0.289
Power Drift [dB]	-0.03	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.3
Dist 3dB Peak [mm]		12.3

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 2, Channel 9262 (1852.400MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	CHEEK, 0.00	Band 2		1852.400, 9262	7.68	1.42	41.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

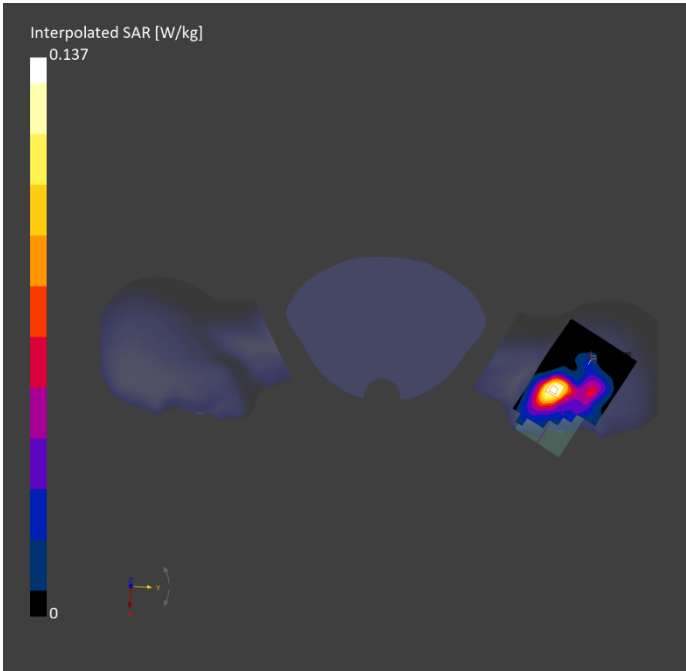
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-26	2026-08-26
psSAR1g [W/kg]	0.113	0.122
psSAR10g [W/kg]	0.067	0.078
Power Drift [dB]	0.00	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		89.4
Dist 3dB Peak [mm]		13.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE BOTTOM, Band 2, Channel 9262 (1852.400MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE BOTTOM, 10.00	Band 2		1852.400, 9262	7.68	1.42	41.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

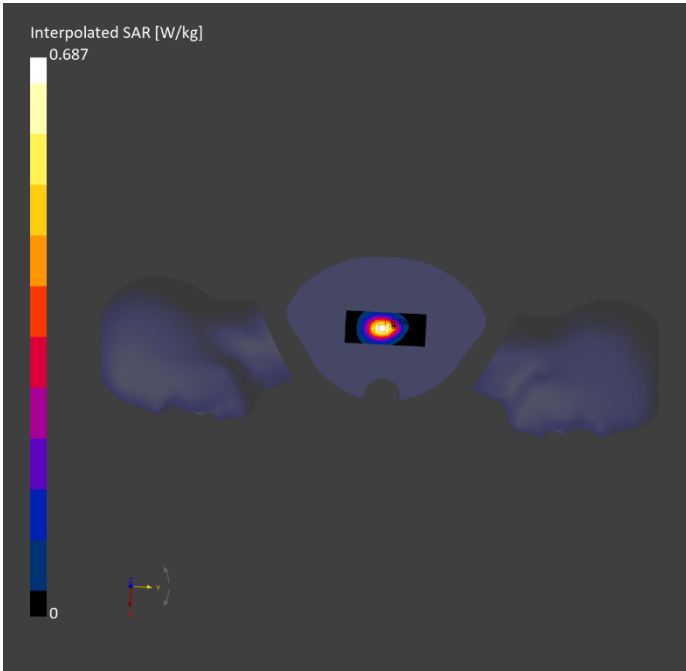
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-26	2026-08-26
psSAR1g [W/kg]	0.556	0.582
psSAR10g [W/kg]	0.308	0.330
Power Drift [dB]	-0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.2
Dist 3dB Peak [mm]		13.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 4, Channel 1513 (1752.600MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	CHEEK, 0.00	Band 4		1752.600, 1513	7.93	1.33	42.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

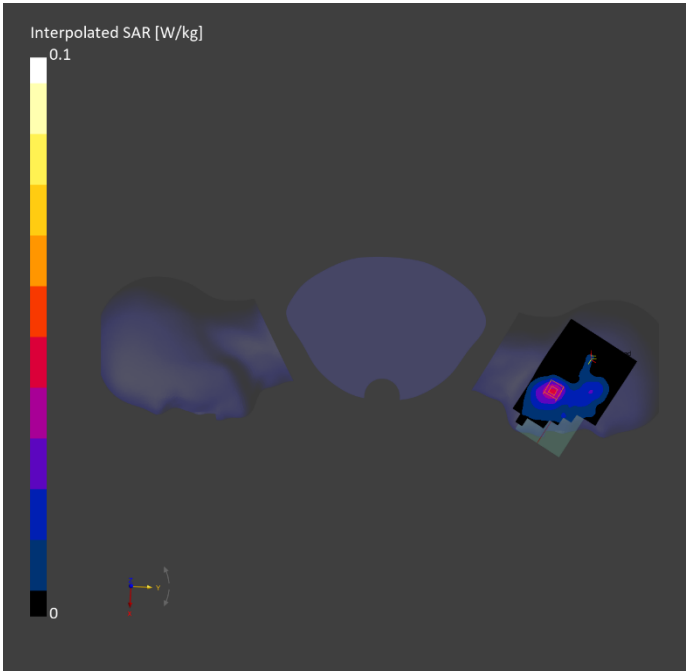
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-24	2026-08-24
psSAR1g [W/kg]	0.036	0.033
psSAR10g [W/kg]	0.021	0.022
Power Drift [dB]	-0.08	-0.26
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.7
Dist 3dB Peak [mm]		15.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE BOTTOM, Band 4, Channel 1513 (1752.600MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE BOTTOM, 10.00	Band 4		1752.600, 1513	7.93	1.33	42.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

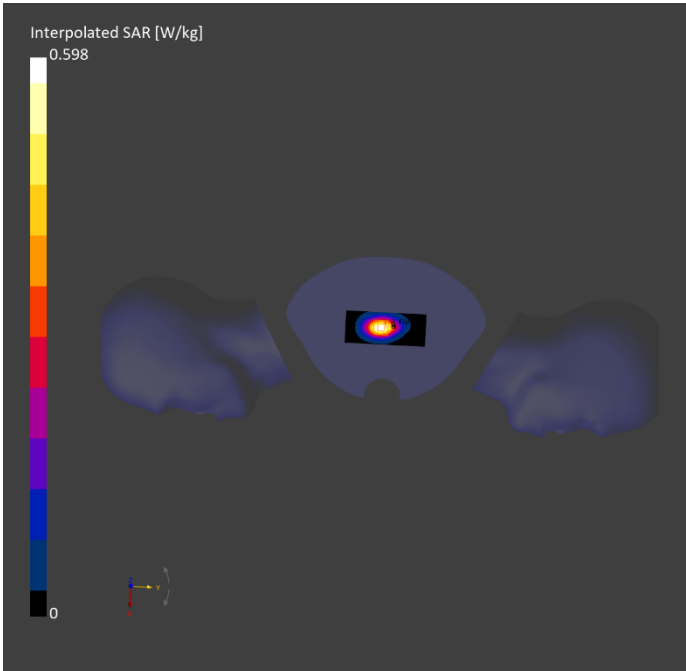
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-24	2026-08-24
psSAR1g [W/kg]	0.482	0.509
psSAR10g [W/kg]	0.264	0.286
Power Drift [dB]	-0.03	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.7
Dist 3dB Peak [mm]		11.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 5, Channel 4132 (826.400MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, Head Simulating Liquid	CHEEK, 0.00	Band 5		826.400, 4132	9.41	0.914	43.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

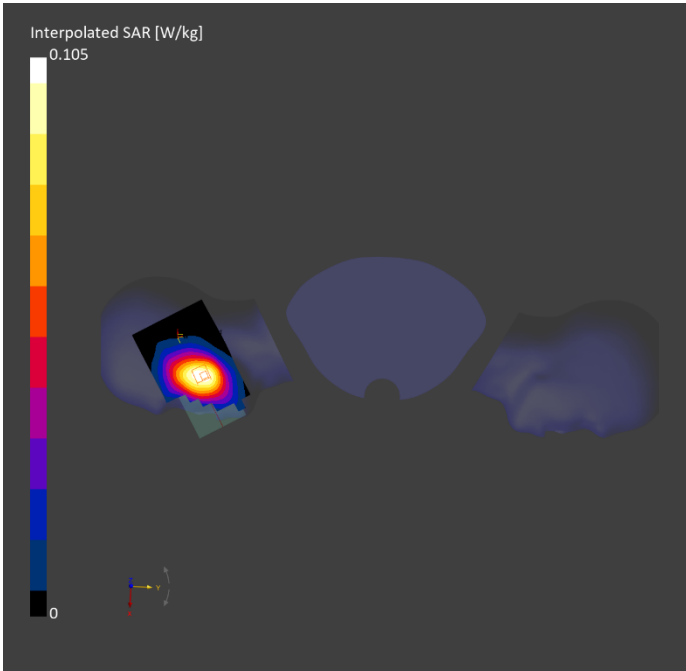
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-20	2026-08-20
psSAR1g [W/kg]	0.091	0.097
psSAR10g [W/kg]	0.063	0.075
Power Drift [dB]	-0.03	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		91.3
Dist 3dB Peak [mm]		22.9

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 5, Channel 4132 (826.400MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 10.00	Band 5		826.400, 4132	9.41	0.914	43.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

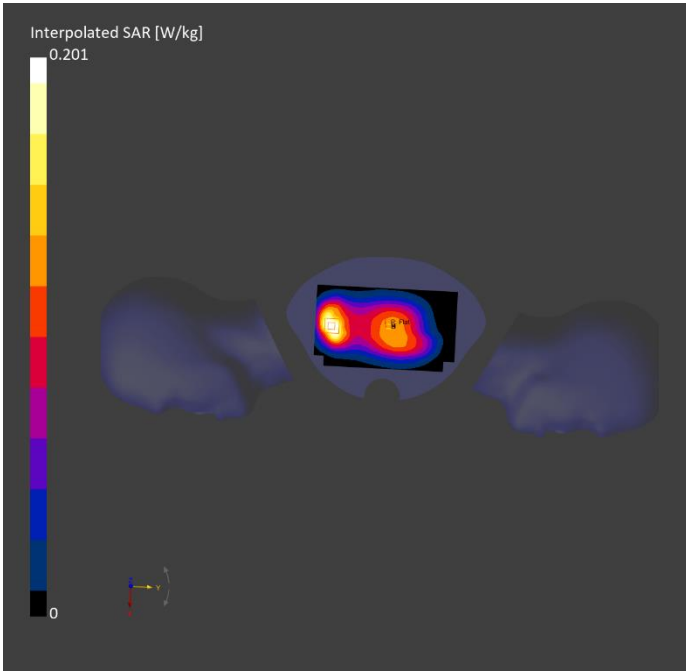
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-20	2026-08-20
psSAR1g [W/kg]	0.176	0.181
psSAR10g [W/kg]	0.117	0.110
Power Drift [dB]	-0.06	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.9
Dist 3dB Peak [mm]		12.6

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, TILT, Band 2, Channel 19100 (1900.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	TILT, 0.00	Band 2		1900.000, 19100	7.68	1.42	41.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

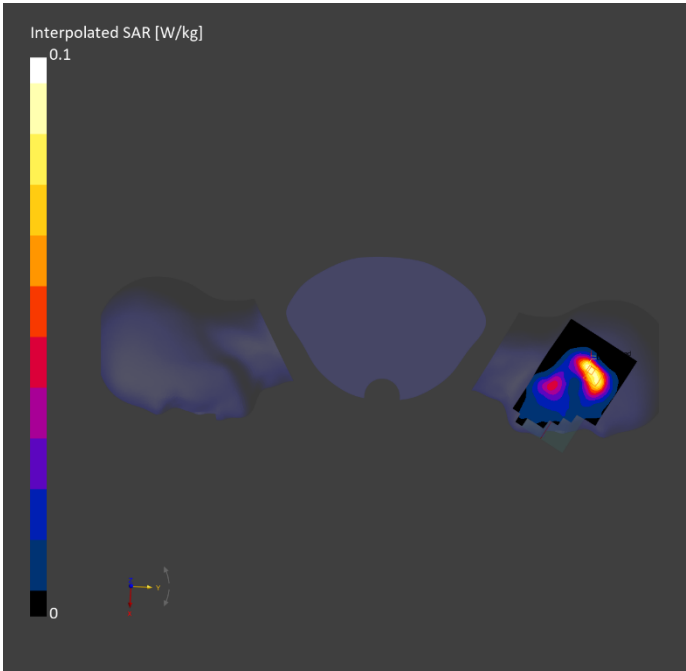
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-26	2026-08-26
psSAR1g [W/kg]	0.074	0.080
psSAR10g [W/kg]	0.043	0.051
Power Drift [dB]	-0.12	-0.15
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		89.2
Dist 3dB Peak [mm]		11.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 2, Channel 19100 (1900.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 10.00	Band 2		1900.000, 19100	7.68	1.42	41.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

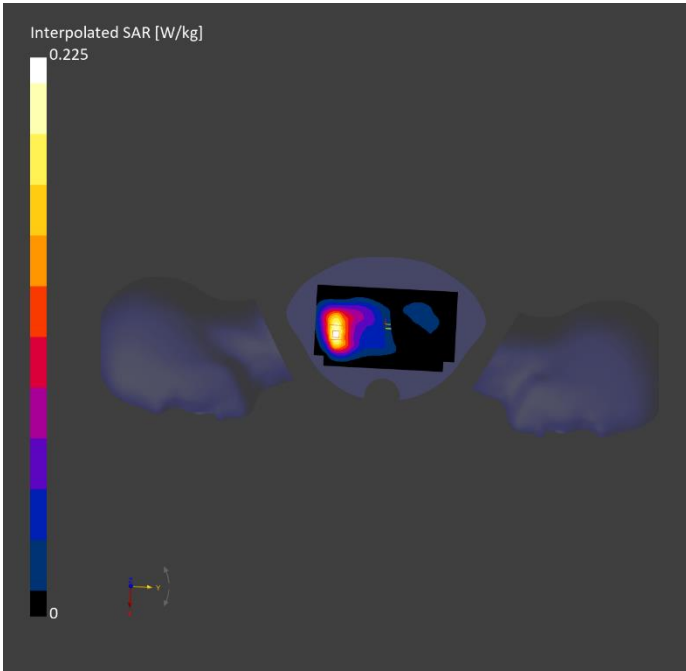
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-26	2026-08-26
psSAR1g [W/kg]	0.181	0.187
psSAR10g [W/kg]	0.103	0.113
Power Drift [dB]	0.00	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.3
Dist 3dB Peak [mm]		12.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 4, Channel 20300 (1745.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	CHEEK, 0.00	Band 4		1745.000, 20300	7.93	1.33	42.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

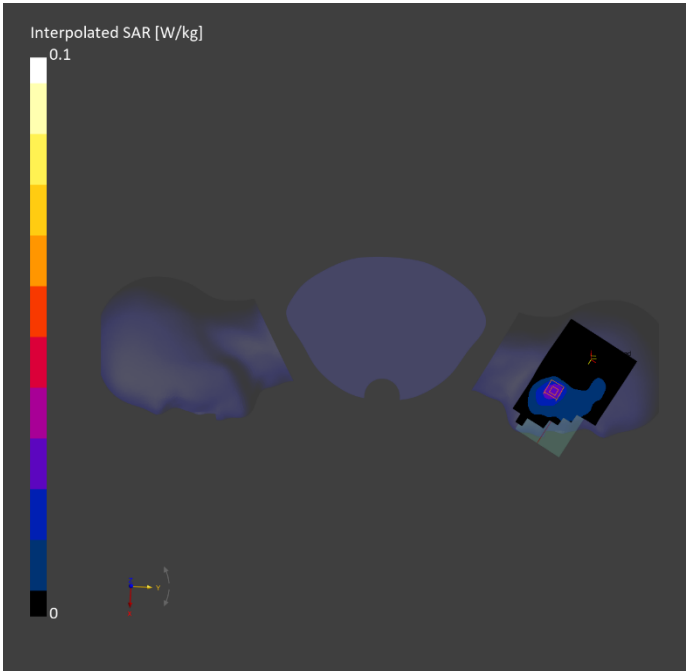
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-24	2026-08-24
psSAR1g [W/kg]	0.027	0.025
psSAR10g [W/kg]	0.016	0.017
Power Drift [dB]	0.16	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		89.8
Dist 3dB Peak [mm]		15.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE BOTTOM, Band 4, Channel 20300 (1745.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE BOTTOM, 10.00	Band 4		1745.000, 20300	7.93	1.33	42.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

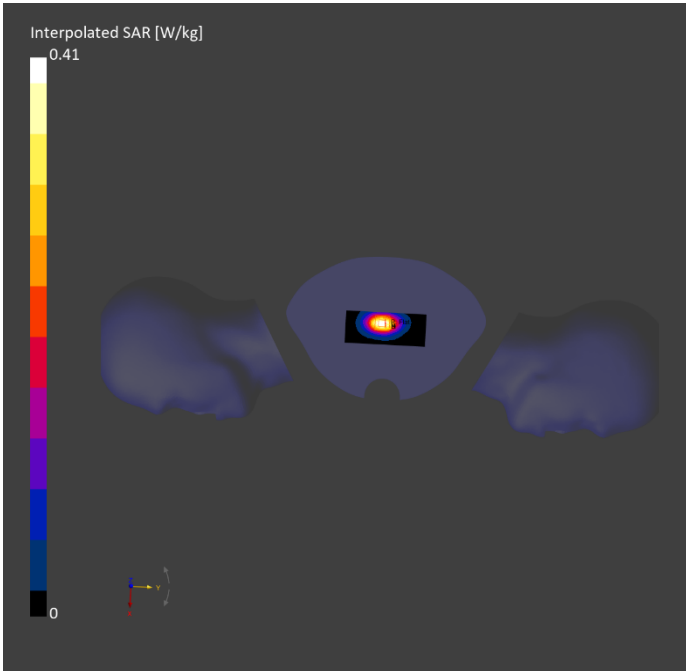
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-24	2026-08-24
psSAR1g [W/kg]	0.334	0.362
psSAR10g [W/kg]	0.183	0.205
Power Drift [dB]	0.05	-0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.8
Dist 3dB Peak [mm]		10.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, TILT, Band 5, Channel 20450 (829.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	TILT, 0.00	Band 5		829.000, 20450	9.41	0.914	43.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

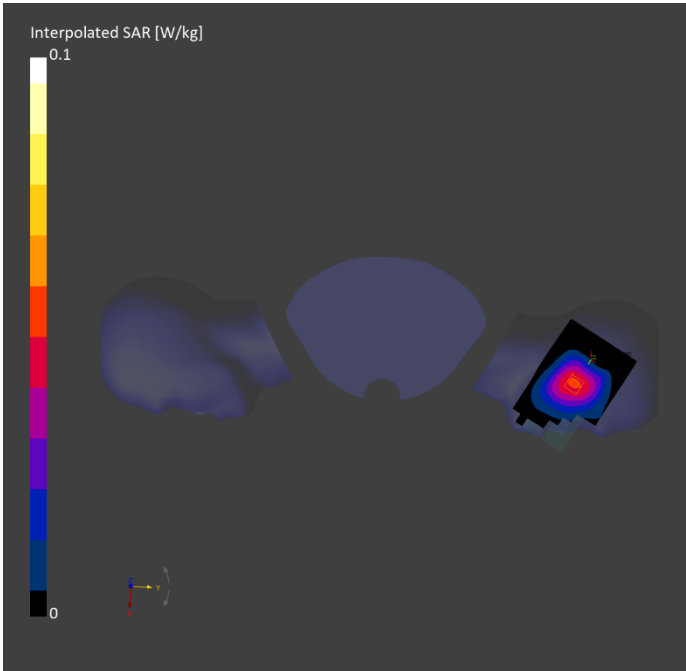
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-20	2026-08-20
psSAR1g [W/kg]	0.046	0.048
psSAR10g [W/kg]	0.032	0.039
Power Drift [dB]	0.02	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		93.1
Dist 3dB Peak [mm]		28.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 5, Channel 20450 (829.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 10.00	Band 5		829.000, 20450	9.41	0.914	43.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

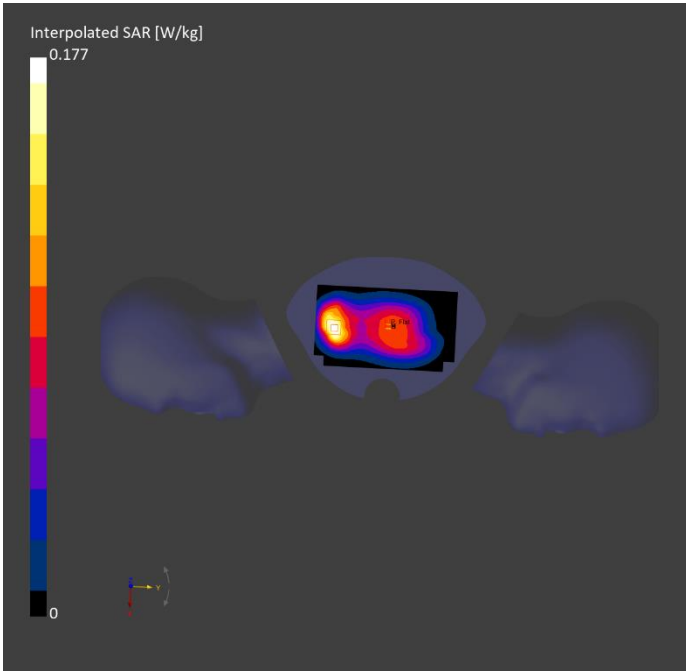
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-20	2026-08-20
psSAR1g [W/kg]	0.154	0.162
psSAR10g [W/kg]	0.101	0.098
Power Drift [dB]	-0.11	-0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.6
Dist 3dB Peak [mm]		11.9

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 7, Channel 20800 (2505.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	CHEEK, 0.00	Band 7		2505.000, 20800	7.26	1.89	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

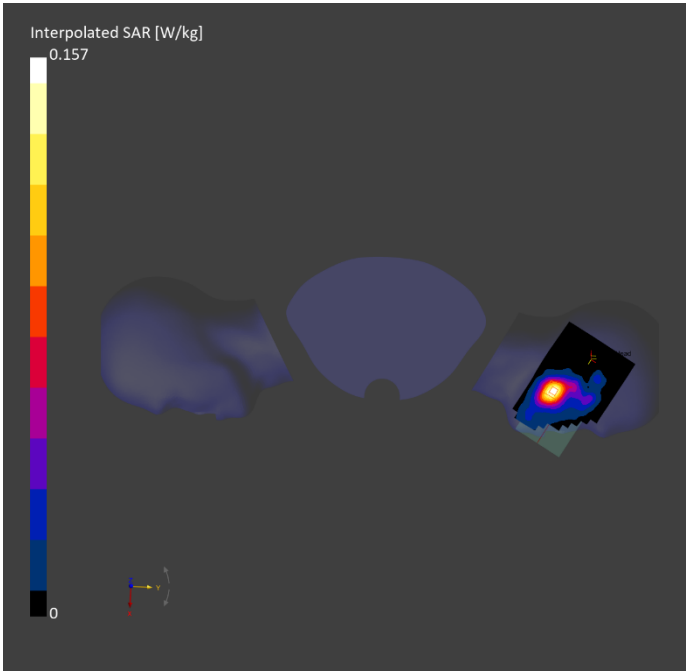
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-31	2026-08-31
psSAR1g [W/kg]	0.124	0.131
psSAR10g [W/kg]	0.065	0.072
Power Drift [dB]	0.05	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.1
Dist 3dB Peak [mm]		12.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE BOTTOM, Band 7, Channel 20800 (2505.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE BOTTOM, 10.00	Band 7		2505.000, 20800	7.26	1.89	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

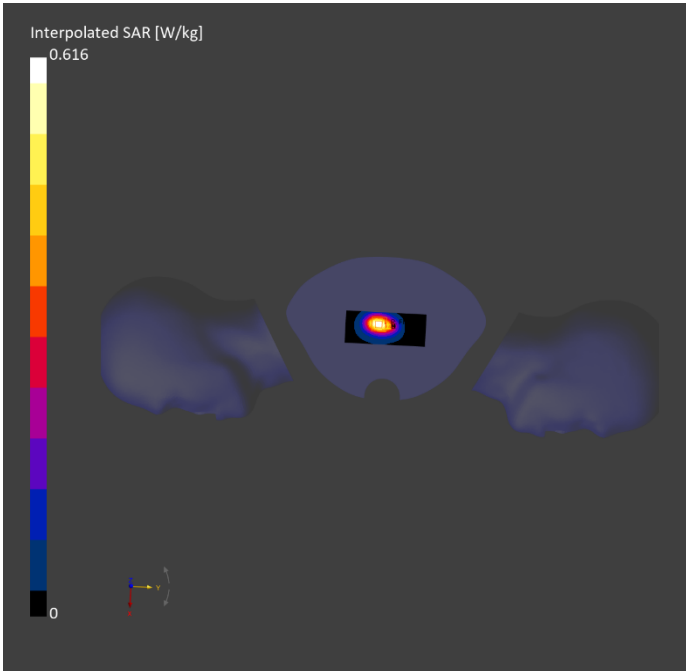
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-31	2026-08-31
psSAR1g [W/kg]	0.479	0.504
psSAR10g [W/kg]	0.236	0.257
Power Drift [dB]	-0.12	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.9
Dist 3dB Peak [mm]		11.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 38, Channel 37800 (2575.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	CHEEK, 0.00	Band 38		2575.000, 37800	7.26	1.94	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

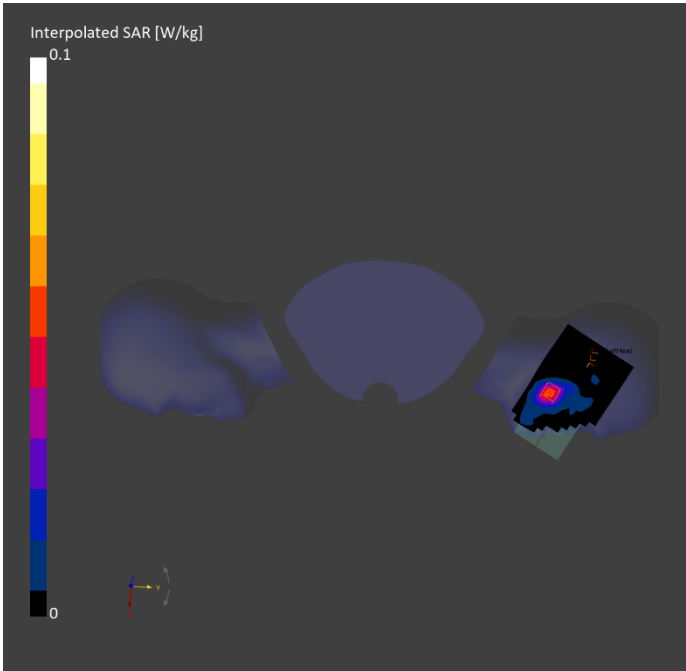
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-31	2026-08-31
psSAR1g [W/kg]	0.045	0.047
psSAR10g [W/kg]	0.023	0.024
Power Drift [dB]	-0.28	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.4
Dist 3dB Peak [mm]		11.9

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE BOTTOM, Band 38, Channel 37800 (2575.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE BOTTOM, 10.00	Band 38		2575.000, 37800	7.26	1.94	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

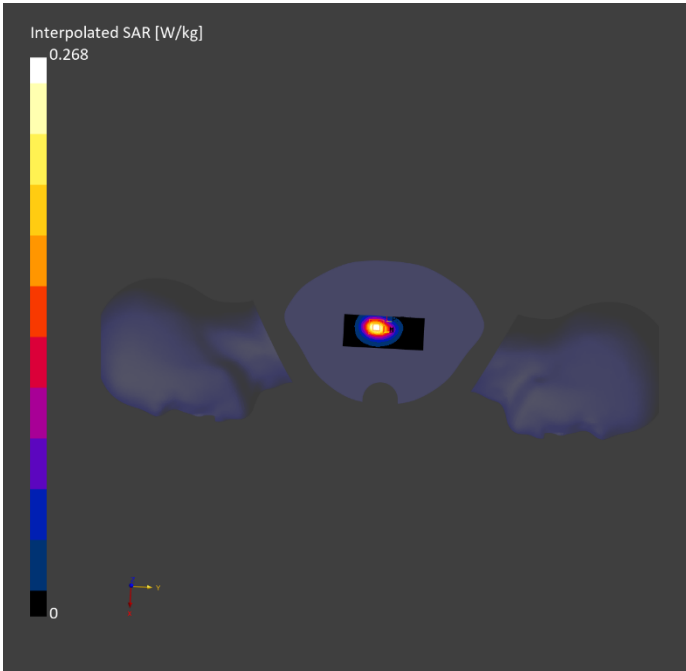
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-31	2026-08-31
psSAR1g [W/kg]	0.208	0.216
psSAR10g [W/kg]	0.101	0.109
Power Drift [dB]	0.04	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.2
Dist 3dB Peak [mm]		11.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 41, Channel 40620 (2593.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	CHEEK, 0.00	Band 41		2593.000, 40620	7.26	1.90	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

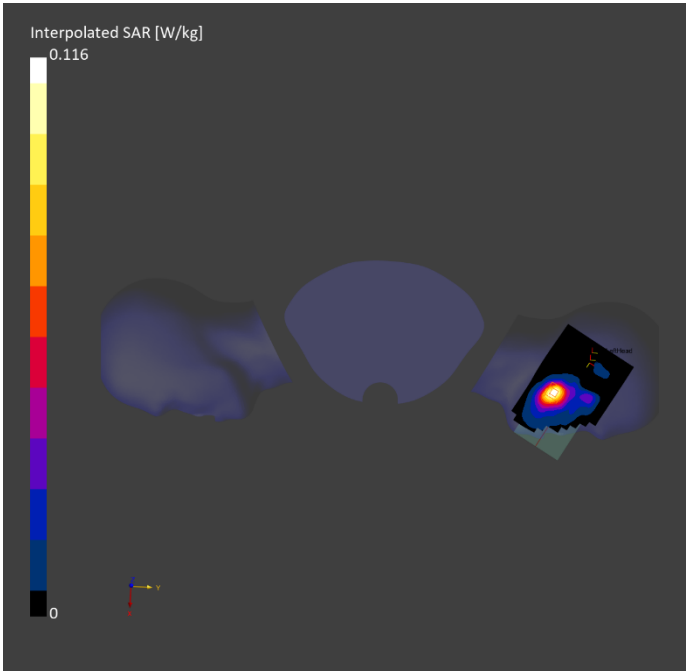
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-09-01	2026-09-01
psSAR1g [W/kg]	0.091	0.093
psSAR10g [W/kg]	0.047	0.049
Power Drift [dB]	-0.48	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.8
Dist 3dB Peak [mm]		11.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE BOTTOM, Band 41, Channel 40620 (2593.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE BOTTOM, 10.00	Band 41		2593.000, 40620	7.26	1.90	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

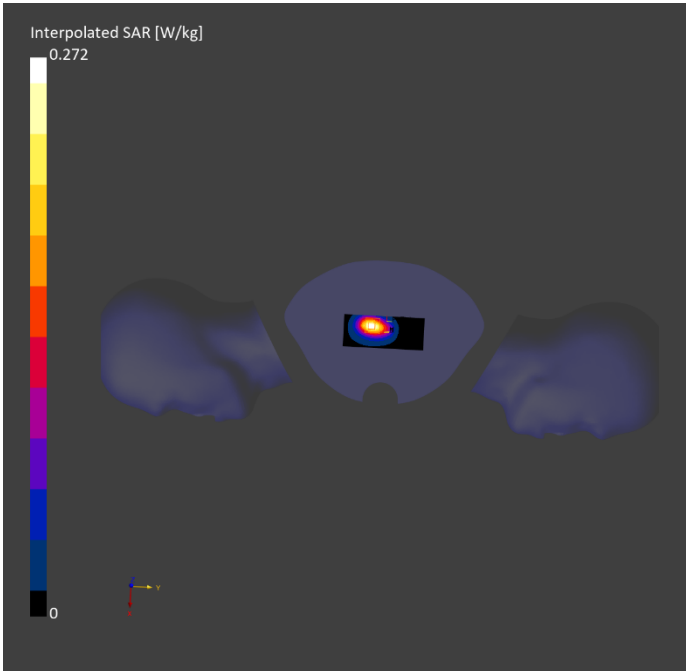
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-09-01	2026-09-01
psSAR1g [W/kg]	0.208	0.216
psSAR10g [W/kg]	0.101	0.109
Power Drift [dB]	0.04	-0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.3
Dist 3dB Peak [mm]		10.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, TILT, 2.4 GHz, Channel 11 (2462.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	TILT, 0.00	2.4 GHz		2462.000, 11	7.11	1.81	41.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

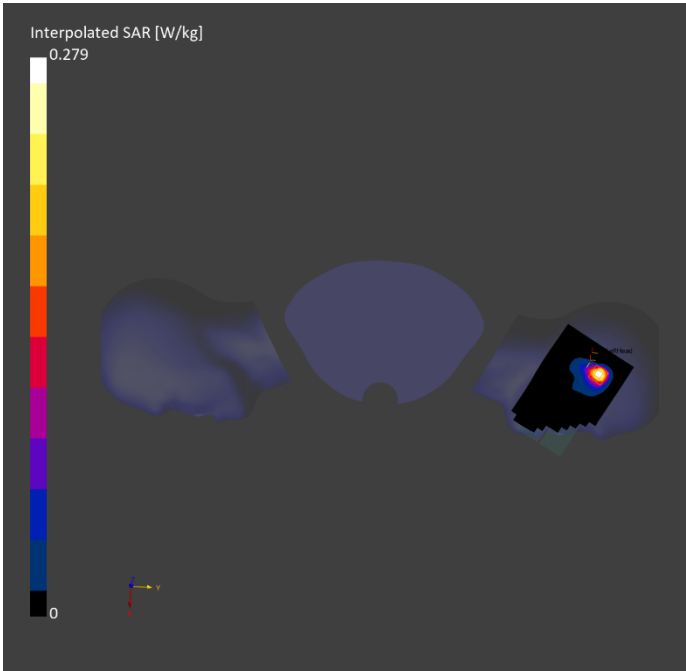
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-28	2026-08-28
psSAR1g [W/kg]	0.216	0.238
psSAR10g [W/kg]	0.10	0.106
Power Drift [dB]	-0.15	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.8
Dist 3dB Peak [mm]		6.9

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, 2.4 GHz, Channel 11 (2462.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 10.00	2.4 GHz		2462.000, 11	7.11	1.81	41.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

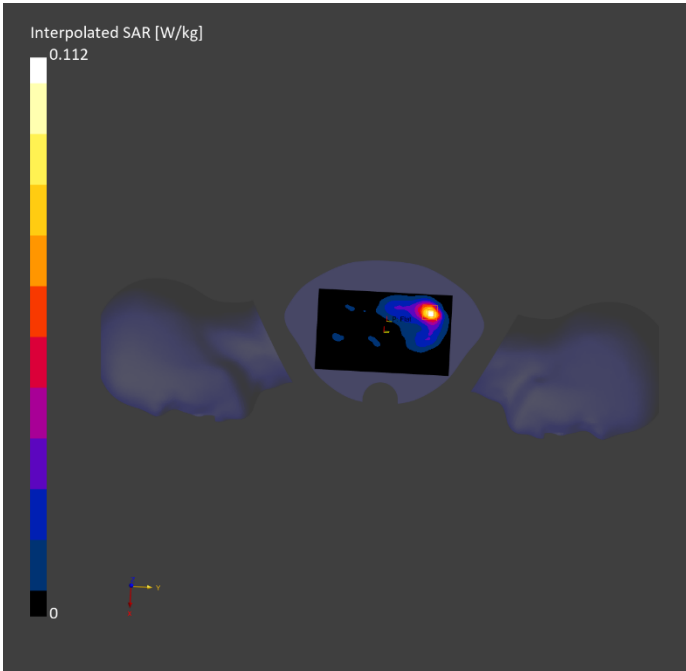
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-28	2026-08-28
psSAR1g [W/kg]	0.084	0.081
psSAR10g [W/kg]	0.039	0.038
Power Drift [dB]	-0.15	-0.39
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.4
Dist 3dB Peak [mm]		10.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, TILT, U-NII 1 / 2A, Channel 38 (5190.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	TILT, 0.00	U-NII 1 / 2A		5190.000, 38	5.48	4.51	36.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

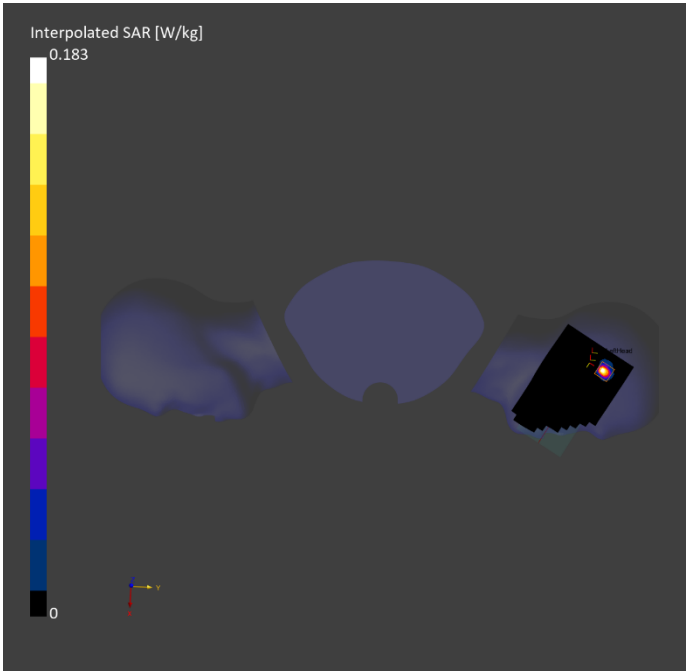
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-09-05	2026-09-05
psSAR1g [W/kg]	0.108	0.115
psSAR10g [W/kg]	0.028	0.027
Power Drift [dB]	-0.24	-0.26
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		59.1
Dist 3dB Peak [mm]		5.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE TOP, U-NII 1 / 2A, Channel 38 (5190.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE TOP, 10.00	U-NII 1 / 2A		5190.000, 38	5.48	4.51	36.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

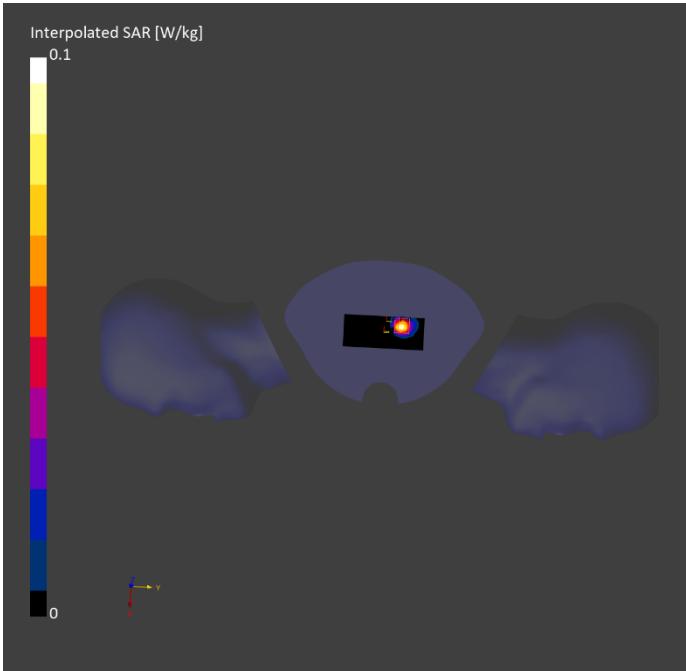
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-09-05	2026-09-05
psSAR1g [W/kg]	0.064	0.068
psSAR10g [W/kg]	0.022	0.021
Power Drift [dB]	0.38	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		59.6
Dist 3dB Peak [mm]		7.3

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, TILT, U-NII 1 / 2A, Channel 52 (5260.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	TILT, 0.00	U-NII 1 / 2A		5260.000, 52	5.29	4.68	36.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

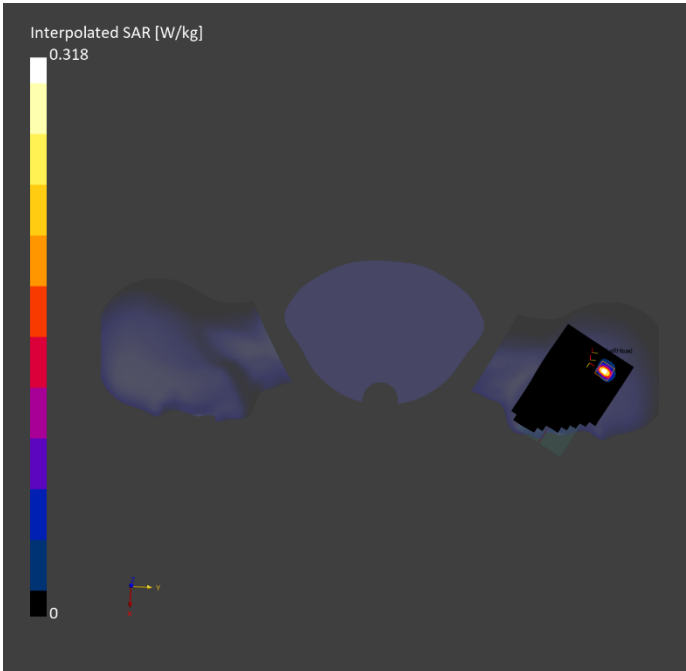
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-09-05	2026-09-05
psSAR1g [W/kg]	0.205	0.221
psSAR10g [W/kg]	0.056	0.052
Power Drift [dB]	0.17	0.15
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		62.7
Dist 3dB Peak [mm]		4.9

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE TOP, U-NII 1 / 2A, Channel 52 (5260.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE TOP, 10.00	U-NII 1 / 2A		5260.000, 52	5.29	4.68	36.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

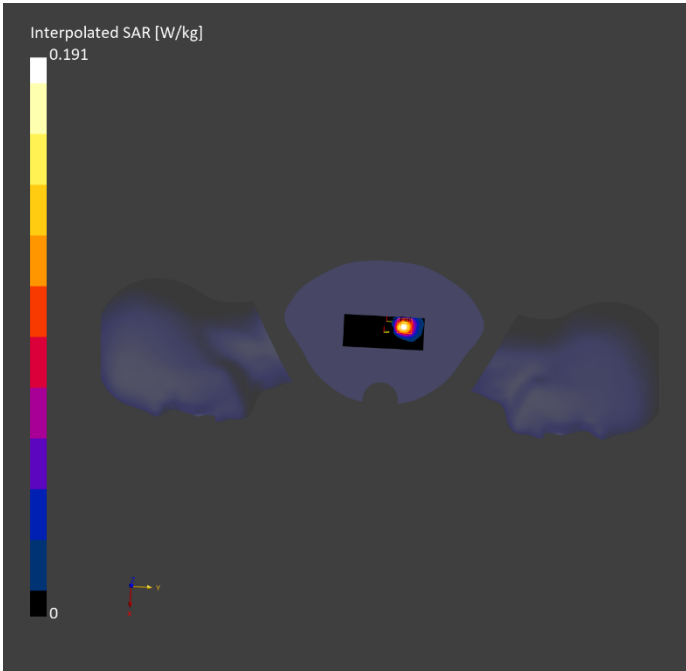
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-09-05	2026-09-0
psSAR1g [W/kg]	0.134	0.144
psSAR10g [W/kg]	0.048	0.049
Power Drift [dB]	0.11	0.31
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		64.5
Dist 3dB Peak [mm]		8.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, TILT, U-NII 2C,Channel 140 (5700.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	TILT, 0.00	U-NII 2C		5700.000, 140	5.03	5.11	35.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

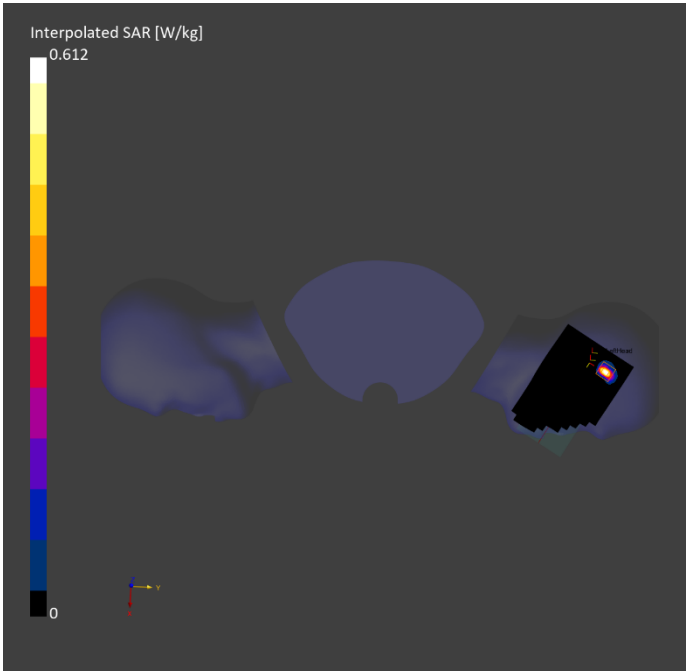
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-09-06	2026-09-06
psSAR1g [W/kg]	0.387	0.423
psSAR10g [W/kg]	0.105	0.116
Power Drift [dB]	-0.20	-0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		56.7
Dist 3dB Peak [mm]		4.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE TOP, U-NII 2C, Channel 140 (5700.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE TOP, 10.00	U-NII 2C		5700.000, 140	5.03	5.11	35.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

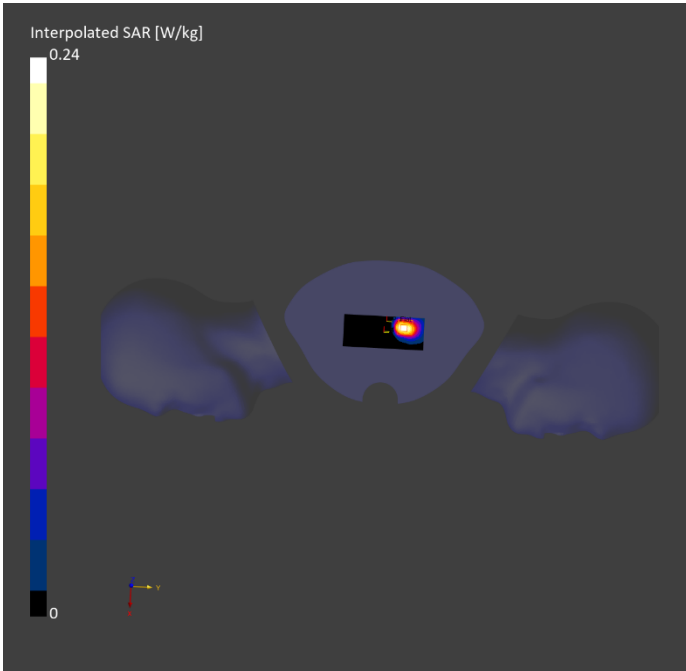
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-09-06	2026-09-06
psSAR1g [W/kg]	0.177	0.185
psSAR10g [W/kg]	0.067	0.066
Power Drift [dB]	0.23	0.10
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		56.2
Dist 3dB Peak [mm]		9.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, TILT, U-NII 3, Channel 149 (5745.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	TILT, 0.00	U-NII 3		5745.000, 149	4.95	5.17	35.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

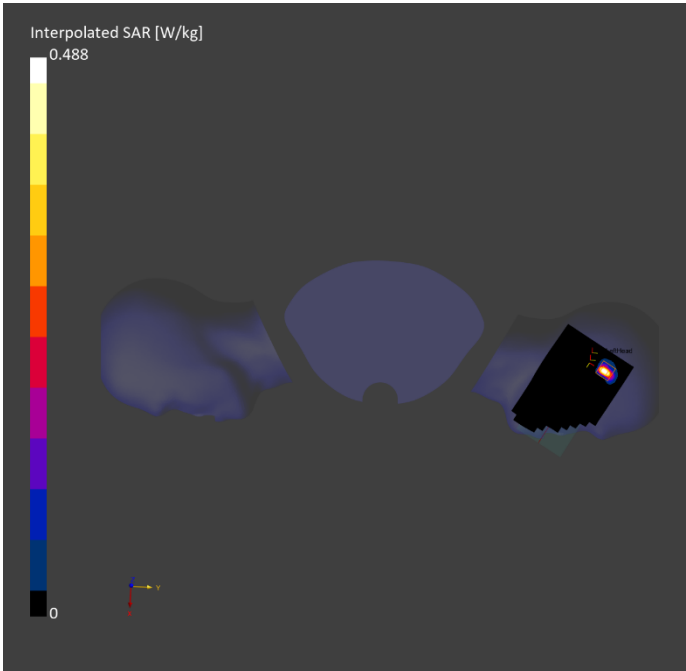
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-09-07	2026-09-07
psSAR1g [W/kg]	0.317	0.333
psSAR10g [W/kg]	0.087	0.094
Power Drift [dB]	-0.06	0.15
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		56.6
Dist 3dB Peak [mm]		4.7

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE TOP, U-NII 3, Channel 149 (5745.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE TOP, 10.00	U-NII 3		5745.000, 149	4.95	5.17	35.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

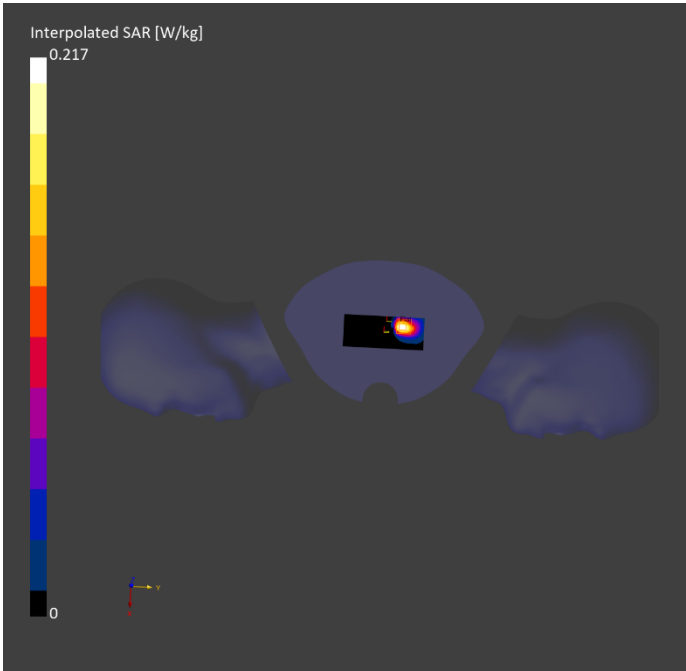
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-09-07	2026-09-07
psSAR1g [W/kg]	0.158	0.170
psSAR10g [W/kg]	0.058	0.058
Power Drift [dB]	-0.12	-0.25
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		55.3
Dist 3dB Peak [mm]		9.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, TILT, ISM 2.4 GHz Band, Channel 39 (2441.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	TILT, 0.00	ISM 2.4 GHz Band		2441.000, 39	7.11	1.82	41.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

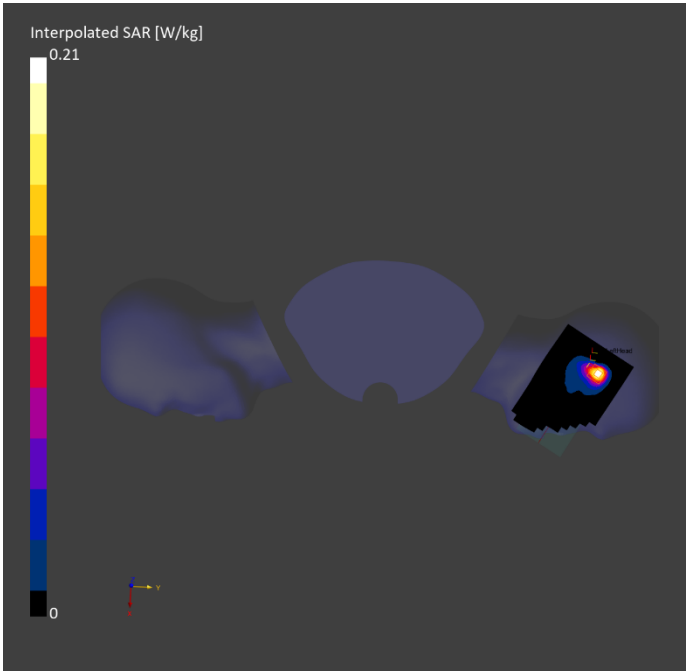
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-28	2026-08-28
psSAR1g [W/kg]	0.161	0.176
psSAR10g [W/kg]	0.074	0.077
Power Drift [dB]	-1.07	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.0
Dist 3dB Peak [mm]		6.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, ISM 2.4 GHz Band, Channel 39 (2441.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 10.00	ISM 2.4 GHz Band		2441.000, 39	7.11	1.82	41.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7960, 2025-10-22	DAE4ip Sn1925, 2025-10-15

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-28	2026-08-28
psSAR1g [W/kg]	0.035	0.034
psSAR10g [W/kg]	0.017	0.015
Power Drift [dB]	-0.31	0.15
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.8
Dist 3dB Peak [mm]		10.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		

